

LA-ICP-MS in gemmology

3rd European Gemmological Symposium, Bern 2009

Presentation: Dr. Michael S. Krzemnicki, FGA
Photos: M.S. Krzemnicki & H.A. Hänni

The daily work of gemologists

- Identification: what is it ?

- Natural or synthetic ?

- Treated or not ?

- The origin: Where does it come from ?



© M.S. Krzemnicki, SSEF

Dumortierite from Tanzania with distinct pleochroism.

Apart from microscopic observations and spectroscopic analyses (UV-Vis, NIR, FTIR, Raman) it is important to have chemical data.

Options for chemical analysis

- X-ray fluorescence (ED-XRF and WD-XRF)
- Energy dispersive spectroscopy coupled with scanning electron microscope (SEM EDS)
- Electron microprobe (EMP)
- Laser induced breakdown spectroscopy (LIBS)
- Laser ablation inductively coupled plasma mass spectrometry (LA-ICP-MS)

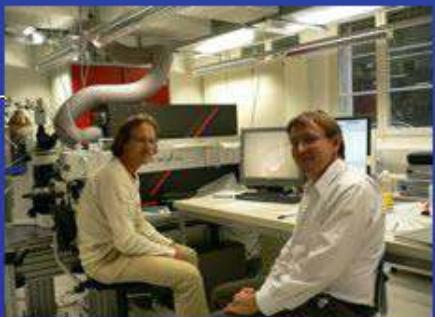


© SSEF Swiss Gemmological Institute

Features of LA ICP MS

Chemical analysis of specimens

- + nearly all chemical elements can be analysed
- + up to 50 elements at the same time
- + point analysis (zoning)
- + only minor sample preparation
- + large dynamic range of analysis
(from sub-ppm to main element concentrations)
- + quantitative data

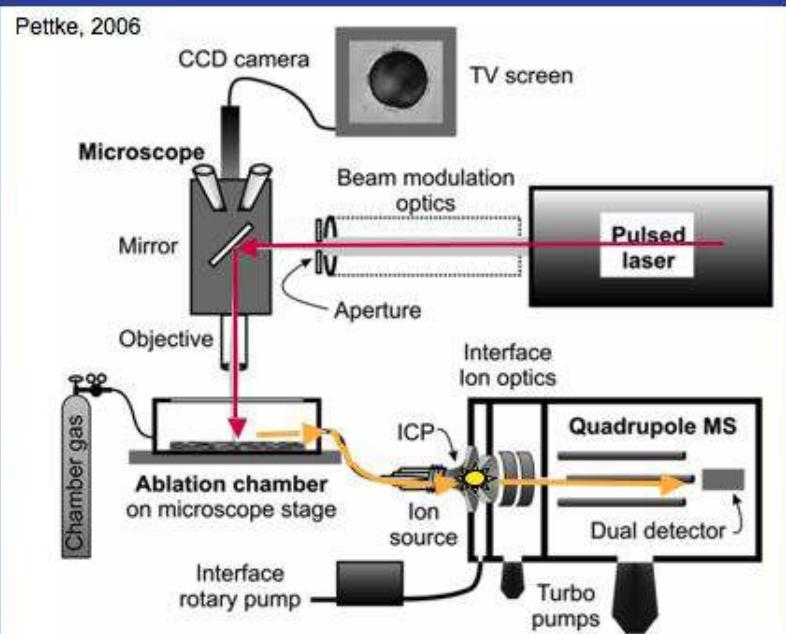


Together with Prof. Thomas Pettke at the LA ICP MS in the Geochemical Lab, University of Berne, Switzerland

- slightly destructive analysis (laser drill holes diameter ca 100 µm)
- how representative are point analyses for the whole stone?
- raw data (qualitative) has to be processed to get quantitative data
- contamination effects
- spike filtering
- highly sophisticated instrument

© SSEF Swiss Gemmological Institute

The LA-ICP-MS instrument



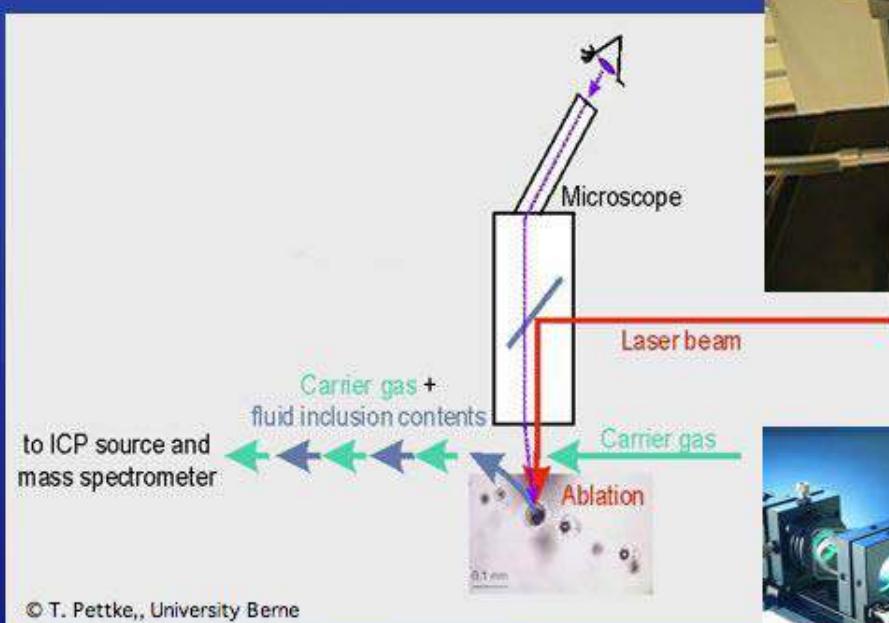
Microlas system:
Beam modulation optics
to homogenize laser
beam energy profile

Lambda Physics, Coherent:
Pulsed nanosecond
ArF excimer laser (193 nm)

Perkin Elmer:
DRC-e quadrupole mass
spectrometer

© SSEF Swiss Gemmological Institute

Laser ablation:



© T. Pettke, University Berne

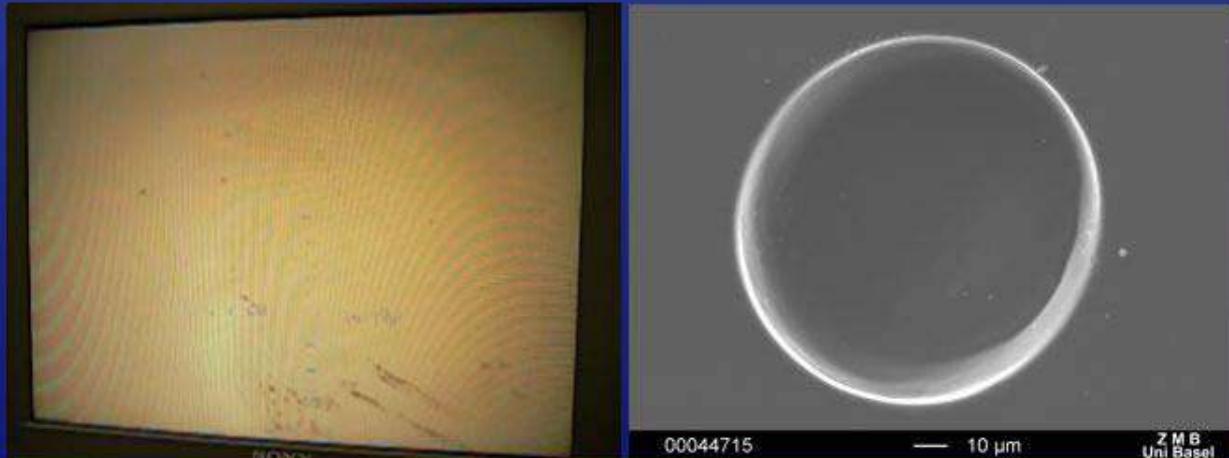


Local heating and vaporization

© SSEF Swiss Gemmological Institute

Laser ablation

- Important factors for analysis:
- laser wavelength (e.g. 193 nm)
 - laser energy (mJ)
 - ablation spot geometry
 - ablation spot diameter and depth
 - ablation pulse length and rate



SEM picture of a laser drill hole

© SSEF Swiss Gemmological Institute

Inductively Coupled Plasma

Important factors:

- plasma flame stability
- carrier gas
- particle size
- ± complete combustion of particles

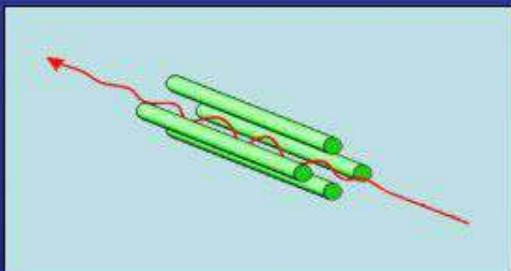


© SSEF Swiss Gemmological Institute

Mass spectrometer

Important factors:

- ions (isotopes) are detected on the basis of their mass/charge ratio
- Beware of superpositions by recombined molecules
(eg. ArO interferes with ^{55}Mn , and ^{56}Fe)



Quadrupole MS



© SSEF Swiss Gemmological Institute

Measuring



- the samples are positioned in the sample chamber together with the standards.
- the sample chamber is then connected with the tubes for floating with the carrier gas.

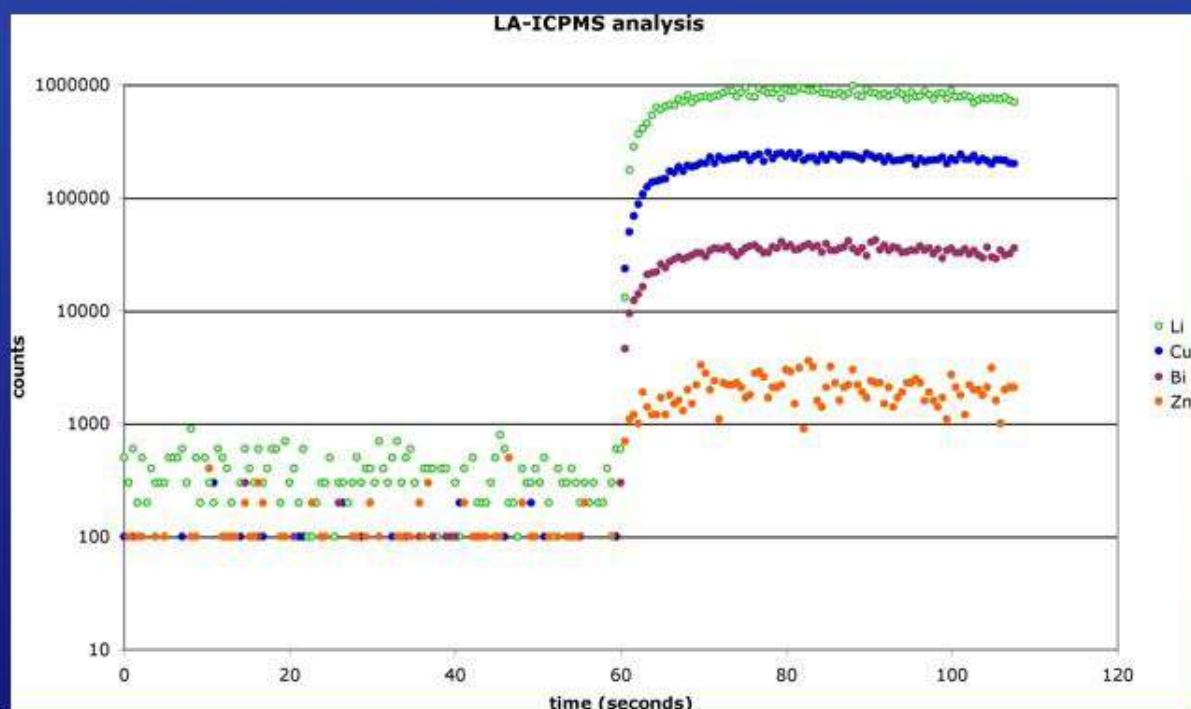


Paraiba-tourmalines from Brazil,
prepared for testing with LA ICP MS

© SSEF Swiss Gemmological Institute

What do we get?

Chemical concentration signal versus time



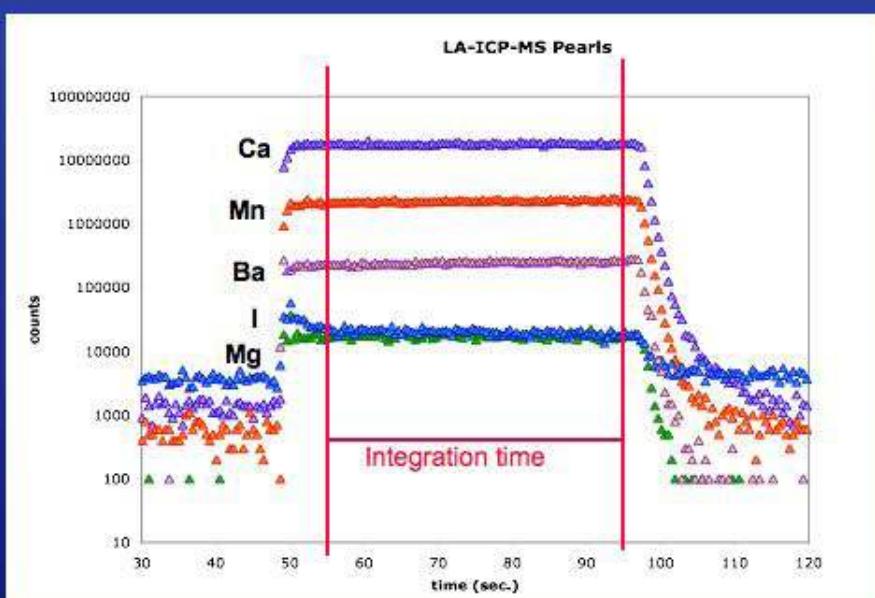
Raw data has to be processed...

© SSEF Swiss Gemmological Institute

Data processing

Using Lamtrace program by S.E. Jackson

homogeneous signal



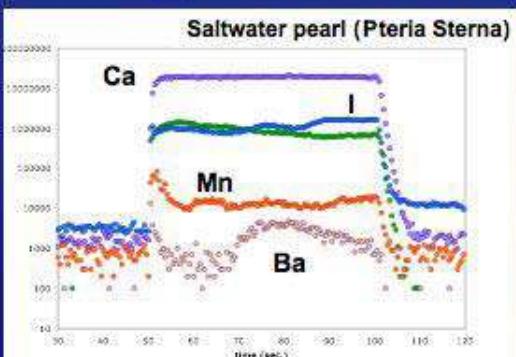
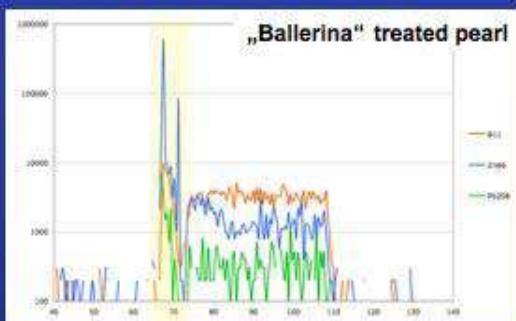
Careful setting of integrals for data processing is important

© SSEF Swiss Gemmological Institute

Data processing

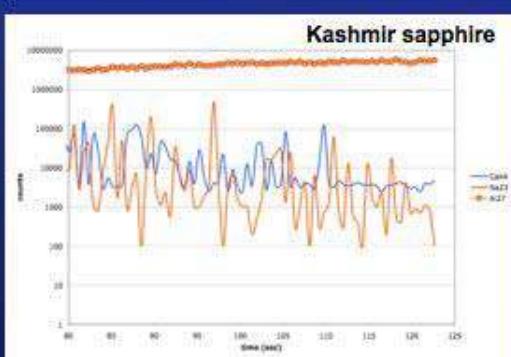
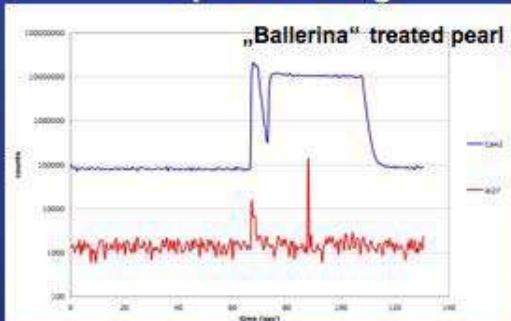
Using Lamtrace program by S.E. Jackson

Surface contamination



zoned signal

Spike filtering



Included

© SSEF Swiss Gemmological Institute

What do we get?

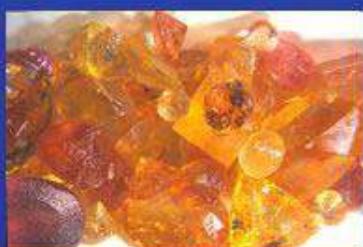
Quantitative chemical data

ORIGIN	Li2O	Be	BeO	Na2O	Mg	Al2O3	K	CaO	Sc	Ti	Zn	MnO	Fe	Ni	CuO	Zn	Ga	Sr	Nb	Sn	Ta	Pb	Bi
	wt%	ppm	wt%	wt%	ppm	wt%	ppm	wt%	ppm	ppm	ppm	wt%	ppm	ppm	wt%	ppm	ppm	ppm	ppm	ppm	ppm	ppm	
Mozambique	1.392	14.793	5.597	2.468	0.494488	42.3	177.8	0.27356	1.198	261.23	1.054	3.847	130.976	2.557	0.363	7.309	379	0.211	2.153	7.555	1.003	40.0	252.038
Mozambique	1.893	14.566	5.571	2.638	0.349761	40.3	190.3	0.24024	1.657	561.70	1.795	4.308	152.740	2.504	0.583	14.613	375	0.262	1.614	6.989	0.766	37.1	228.025
Mozambique	1.392	14.793	5.597	2.468	0.494488	42.3	177.8	0.27356	1.198	261.23	1.054	3.847	130.976	2.557	0.363	7.309	379	0.211	2.153	7.555	1.003	40.0	252.038
Mozambique	1.688	3.550	5.667	2.446	1.380952	41.1	199.0	0.08819	2.755	425.80	1.117	3.960	950.372	1.955	0.225	54.830	418	0.081	0.444	6.940	0.350	8.1	25.444
Mozambique	1.326	6.182	5.484	2.098	0.304554	44.6	141.0	0.10261	1.446	79.64	0.363	1.180	10.968	1.466	0.177	0.933	446	0.027	0.549	4.612	0.340	5.3	49.574
Mozambique	2.043	6.187	5.252	1.946	0.476398	42.9	122.2	0.14390	0.765	6.35	0.203	0.739	14.520	>0.785	0.036	0.532	533	<0.017	1.107	4.982	0.316	7.1	64.244

ORIGIN	MnO wt%	Fe ppm	Ni ppm	CuO wt%	Zn ppm	Ga ppm	Sr ppm	Nb ppm	Sn ppm	Ta ppm	Pb ppm	Bi ppm
Mozambique	3.847	130.976	2.557	0.363	7.309	379	0.211	2.153	7.555	1.003	40.0	252.038
Mozambique	4.308	152.740	2.504	0.583	14.613	378	0.262	1.614	6.989	0.766	37.1	228.025
Mozambique	3.847	130.976	2.557	0.363	7.309	379	0.211	2.153	7.555	1.003	40.0	252.038
Mozambique	3.960	950.372	1.955	0.225	54.830	418	0.081	0.444	6.940	0.350	8.1	25.444
Mozambique	1.188	10.968	1.466	0.177	0.933	446	0.027	0.849	4.612	0.540	8.3	49.574
Mozambique	0.125	14.520	<0.785	0.036	0.532	533	<0.017	1.107	4.982	0.516	7.1	64.244

© SSEF Swiss Gemmological Institute

Research at SSEF using LA-ICP-MS

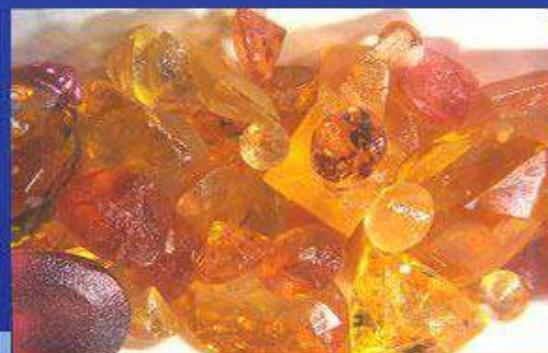


- Beryllium-diffusion treated orange sapphires
- Beryllium diffusion treated blue sapphires
- Beryllium in untreated sapphires
- Chrysoberyl grown on sapphire
- Alexandrite from different origins
- Emeralds from different origins
- Pezzottaite from Madagascar and Afghanistan
- Shells, Pearls and treated pearls
- Musgravite and Taaffeite
- Vanadium tourmaline from Madagascar
- Cu-Mn bearing tourmaline from Brazil, Nigeria and Mozambique
- Colour zoning in corundum
- Spinel from different origins



© SSEF Swiss Gemmological Institute

1. Example: beryllium diffusion treated orange sapphire



Sapphire: LA-ICPMS Resultate

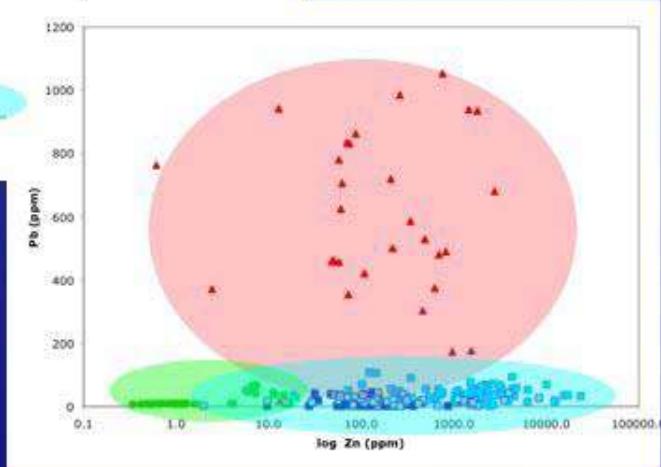
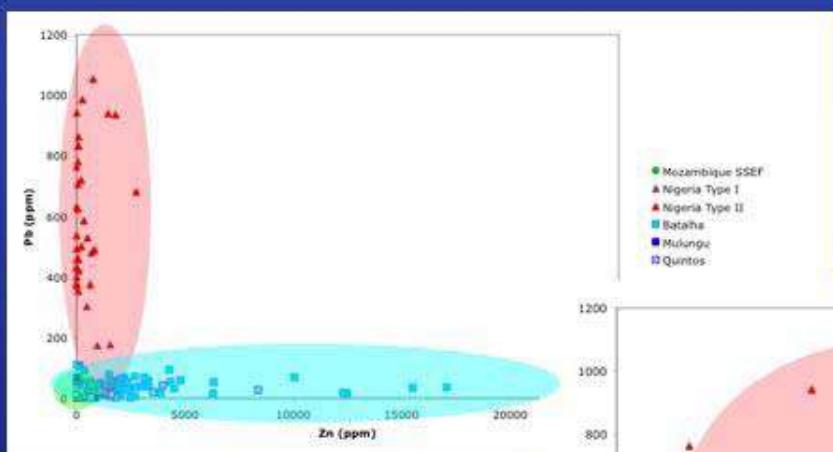
Comments measured mass	Be 9.00 ppm	Na 23.00 ppm	Mg 25 ppm	Al2O3 27.0 wt%	Si 29 ppm	P 31 ppm	Ti 49 ppm	V 51.0 ppm	Cr 53.0 ppm	Mn 55.00 ppm	Fe 57 ppm	Zn 66.0 ppm	Ga 71 ppm	Zr 90.000 ppm
Saph K, profile, rim	6.55	0.37	65	99.8	222	12	76	12.5	423.2	0.15	1516	0.8	54	<0.013
Saph K, profile	6.97	0.37	63	99.8	159	10	75	12.5	413.5	<0.30	1516	0.8	54	<0.008
Saph K, profile	5.02	<0.37	71	99.8	173	11	78	13.4	453.9	<0.31	1702	0.7	57	<0.015
Saph K, profile	4.74	1.41	74	99.8	192	12	80	14.2	482.1	<0.49	1803	0.9	62	<0.015
Saph K, profile	3.31	0.62	71	99.8	251	13	79	14.2	468.0	<0.39	1889	0.8	61	<0.016
Saph K, profile	4.22	0.89	72	99.8	212	15	82	14.6	479.8	<0.31	1819	0.7	62	<0.026
Saph K, profile	3.10	<0.82	69	99.8	157	14	83	14.9	485.8	<0.88	1866	1.0	63	<0.027
Saph K, profile, core	1.98	<0.74	67	99.8	243	15	74	14.5	474.9	<0.41	1858	0.9	62	0.017
Saph K, profile, core	2.86	0.74	68	99.8	200	13	77	14.1	468.9	<0.54	1842	1.1	60	<0.022
Saph K, profile	2.80	0.74	72	99.8	237	13	81	14.4	500.1	<0.31	1912	1.2	64	<0.024
Saph K, profile	4.18	1.41	65	99.8	218	13	79	14.1	479.8	<0.49	1990	0.7	61	<0.026
Saph K, profile	4.28	0.89	66	99.8	176	10	77	13.3	441.5	<0.39	1757	0.7	57	<0.013
Saph K, profile	5.11	1.19	64	99.8	151	11	77	15.3	464.5	<0.31	1702	1.0	55	<0.013

© SSEF Swiss Gemmological Institute

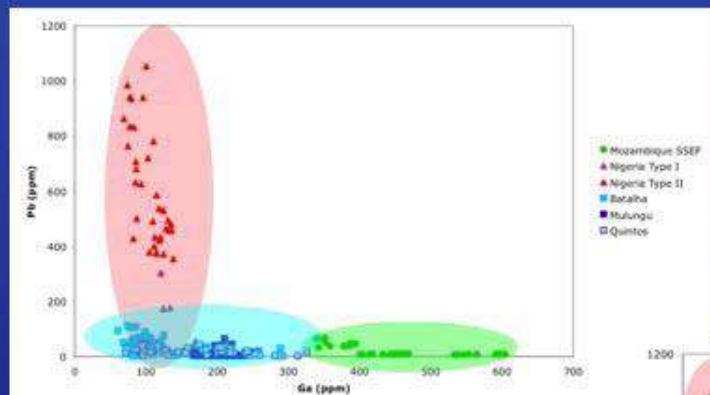
Copper-bearing Tourmaline („Paraiba“)



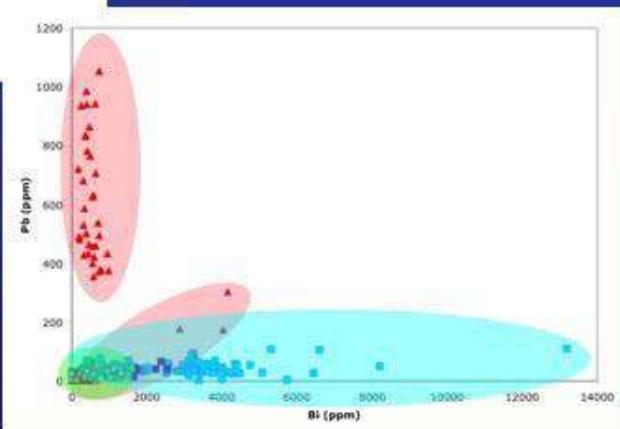
LA ICP MS analysis of „Paraiba“ tourmaline:



LA ICP MS analysis of „Paraiba“ tourmaline:



Pb versus Ga (ppm)



Pb versus Bi (ppm)

© SSEF Swiss Gemmological Institute

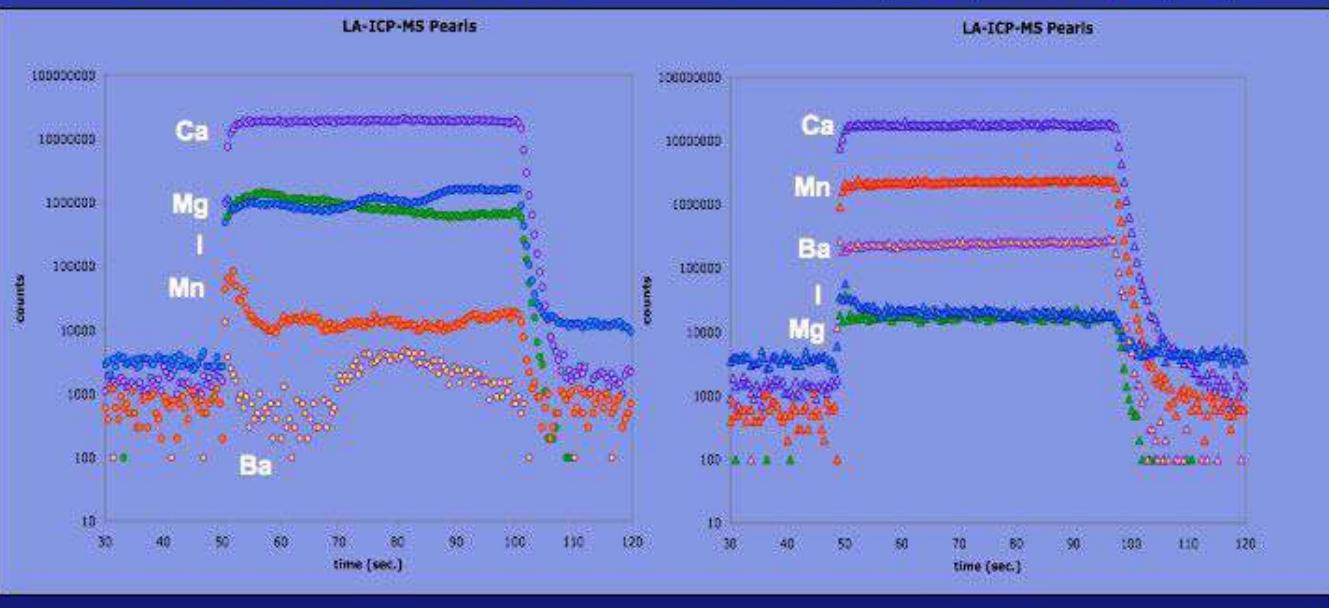


© SSEF Swiss Gemmological Institute

LA ICP MS analysis of Pearls

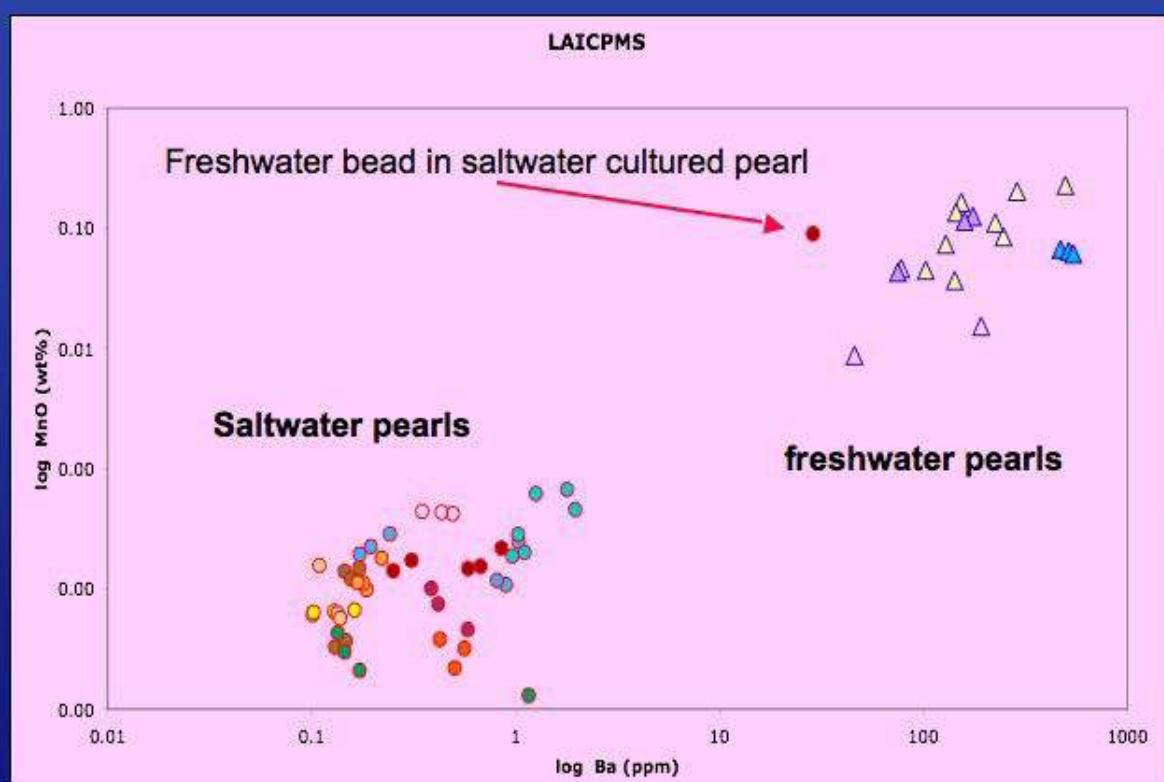
Saltwater pearl (Pteria Serna)

freshwater pearl (China, Hyriopsis)



© SSEF Swiss Gemmological Institute

LA ICP MS analysis of Pearls



© SSEF Swiss Gemmological Institute

Unheated sapphire from Kashmir of 42.29 ct



Colour zoning in corundum

Corundum from Winza, Tanzania



Beryllium in sapphire



3-dimensional jellyfish-like internal structures in Be-diffusion treated sapphires.

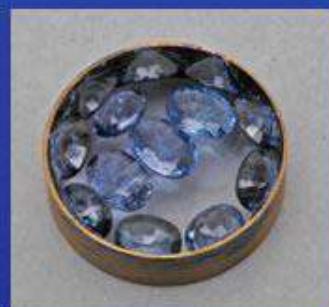
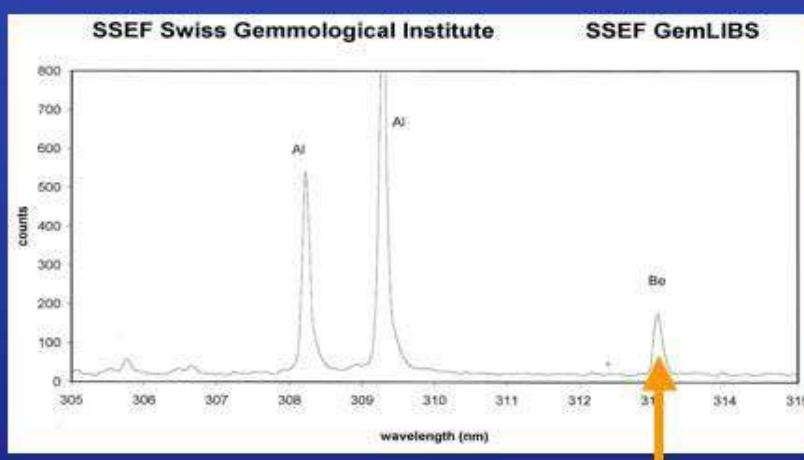
© GAAJ



Planar curved structures in basaltic sapphire

© SSEF Swiss Gemmological Institute

Beryllium in diffusion treated sapphire



LLD FACTOR = 1				LAM-ICP-MS RESULTS - DETECTION LIMIT FILTERED									
samples	wt%	colour	origin	inclusions cloudy diffusion features & curved dust tracks	LAICPMS Be concentration	Filter = <1 X LLD/ isotopic mass	Li 7	Be 9	B 11	Na2O 23	MgO 25	Al2O3 27	
22nog12	SNBL Be_01	0.796	blue	distinct	moderate		0.156	7.907	2.859	0.000007	0.00870	99.8	
22nog13							<0.339	8.114	4.675	0.000187	0.01016	99.8	
22nog14							<0.135	5.511	3.049	0.000022	0.00527	99.8	
22nog06	SNBL Be_02	0.811	blue	moderate	moderate		<0.264	9.078	4.587	<0.000007	0.00858	99.8	
22nog07							<0.256	7.676	5.574	0.000041	0.00948	99.8	
22nog08							Na contamination	<0.214	8.708	4.864	0.000126	0.01054	99.8

© SSEF Swiss Gemmological Institute

Beryllium in untreated sapphire

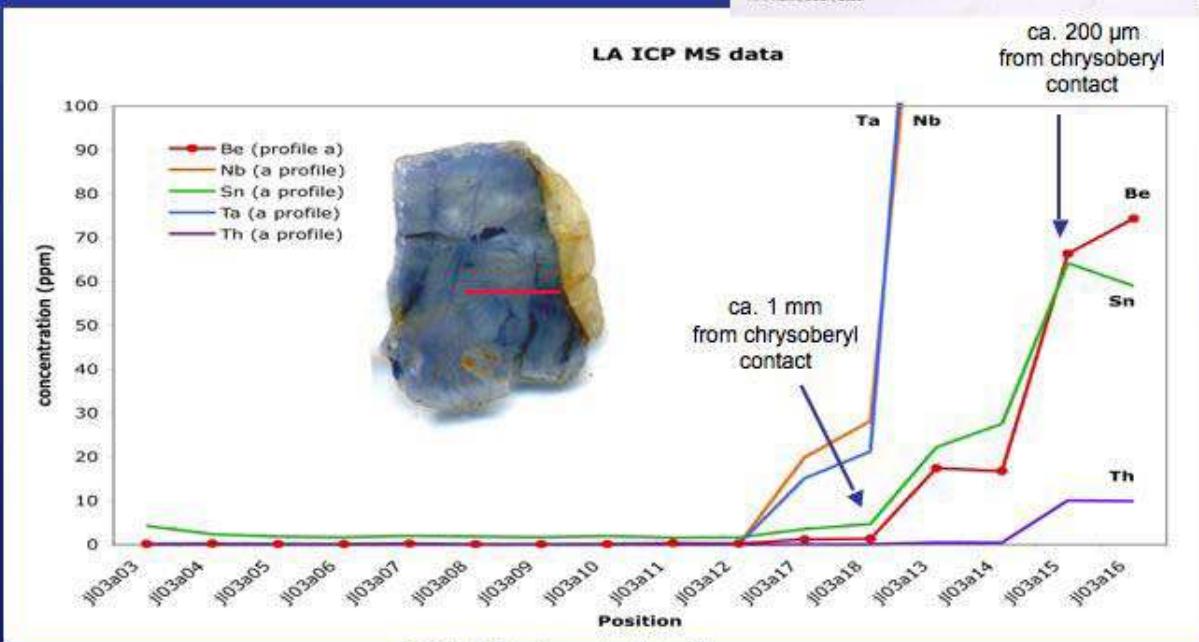


Some sapphires may contain locally low amounts of beryllium.

LLD FACTOR =	Comments	LAM-ICP-MS RESULTS - DETECTION LIMIT FILTERED user = GAAJ and Vincent sapphires, Madagascar, no heat; file = 21feb0.					
		Filter = <1 Li- Isotopic ms:	Be	B	Na2O	MgO	Al2O3
		ppm	ppm	ppm	wt%	wt%	wt%
21feb15	MIMK 005, 120 µm	<0.073	0.312	0.556	<0.000005	0.002004	99
21feb16		<0.157	<0.280	0.747	<0.000005	0.002797	99
21feb17		<0.194	<0.474	<0.426	<0.000005	0.003125	99
21feb18		<0.169	<0.328	0.580	<0.000004	0.003442	99
21feb03	MIMK002, 120 µm	<0.220	<0.439	<0.797	<0.000007	0.00365	99
21feb04		<0.273	<0.572	<0.607	<0.000006	0.00437	99
21feb05		<0.112	<0.416	<1.112	<0.000006	0.00431	99
21feb12	MIMK004, 120 µm	<0.251	<0.613	0.577	0.000009	0.02340	99
21feb13		<0.357	<0.594	<0.870	<0.000007	0.01899	99
21feb14		<0.404	2.004	<1.144	<0.000009	0.03307	99
21feb15		<0.170	<0.551	<0.892	<0.000010	0.01832	99
21feb16		0.296	1.446	<1.028	0.000008	0.03156	99

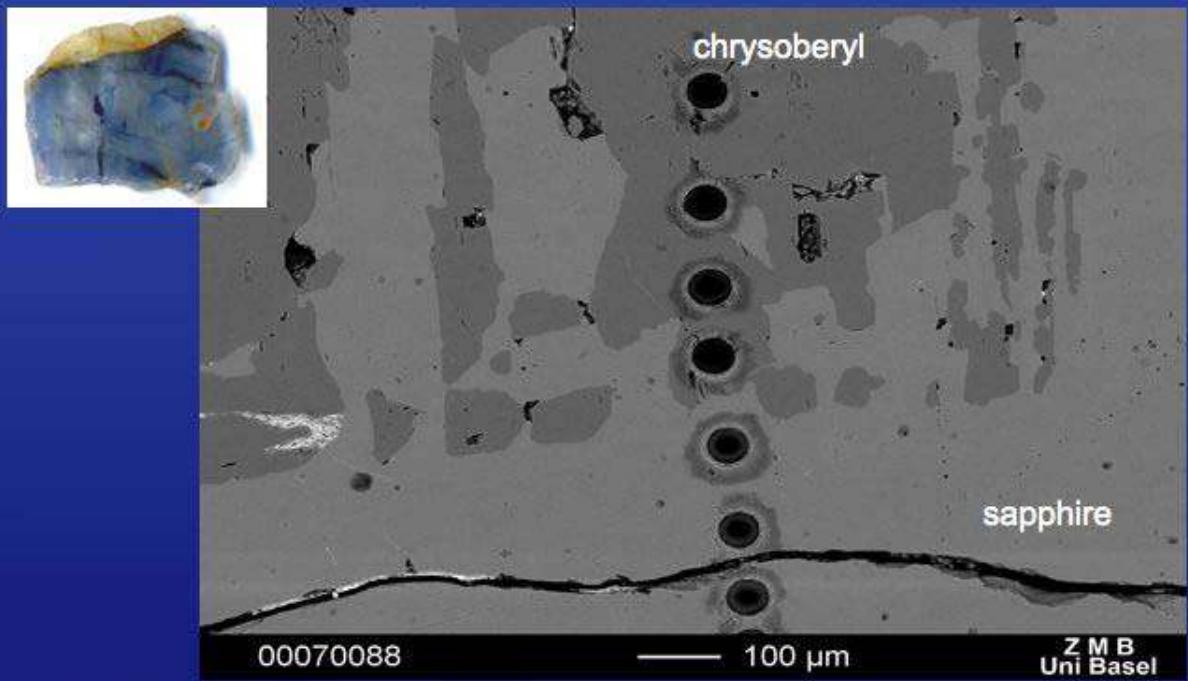
© SSEF Swiss Gemmological Institute

Chrysoberyl on Sapphire



© SSEF Swiss Gemmological Institute

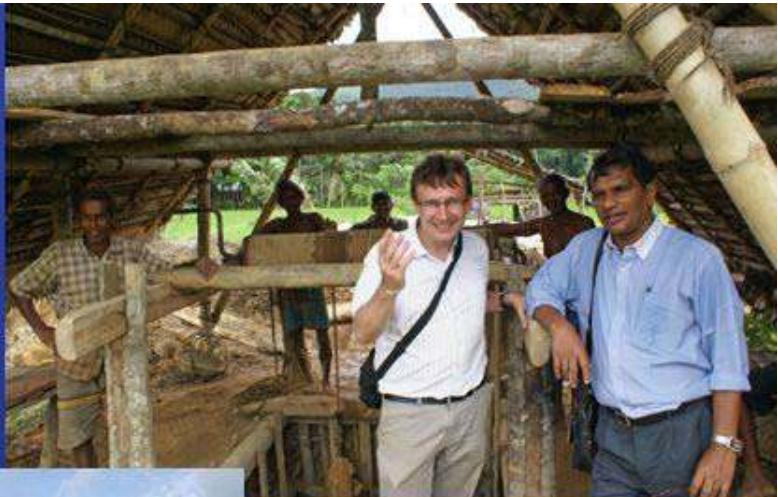
Chrysoberyl on Sapphire

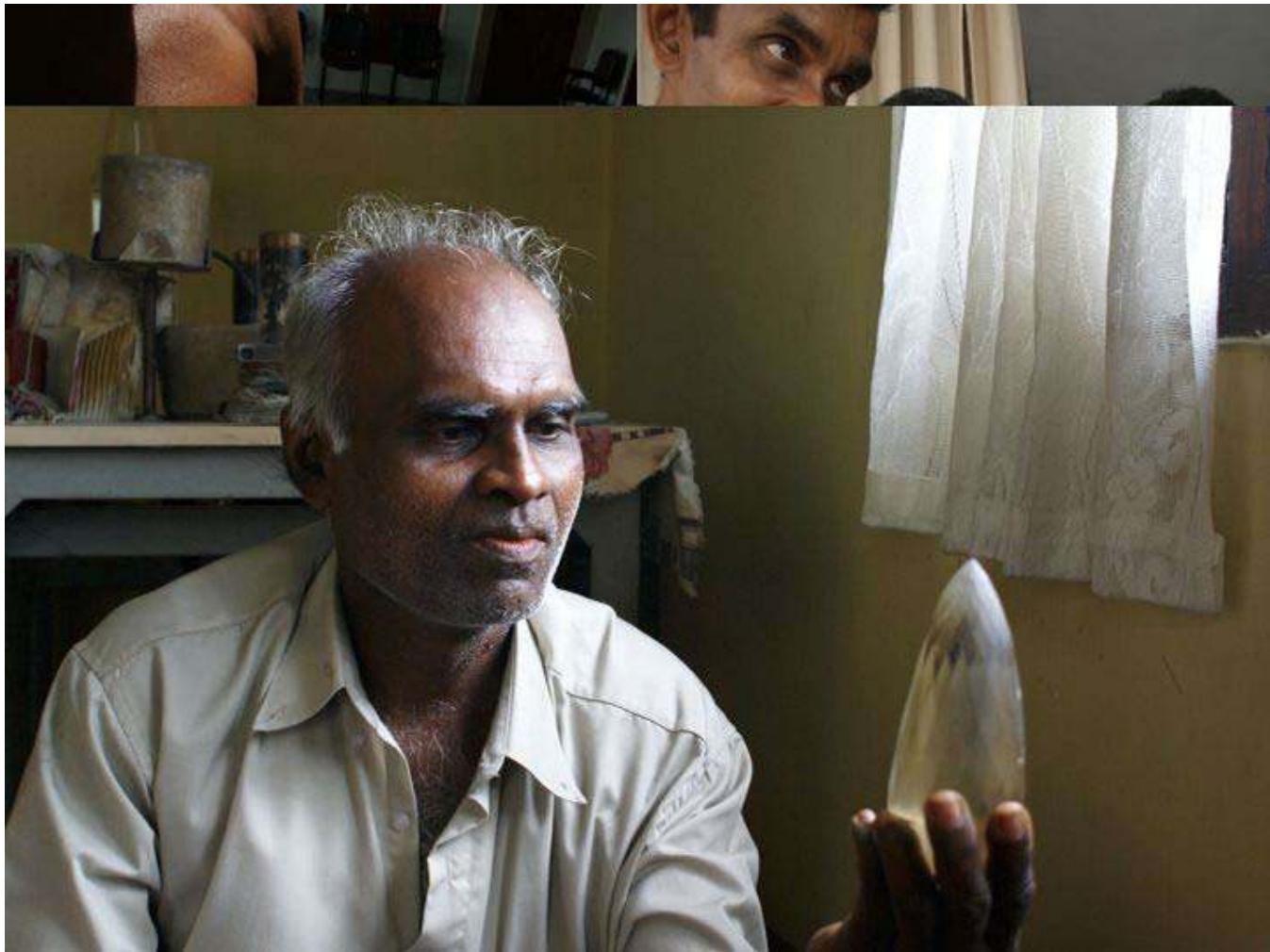


SEM micrographs (backscattered electrons), showing a dense syngenetic intergrowth of chrysoberyl with sapphire

© SSEF Swiss Gemmological Institute

Last week in Sri Lanka...





Thank you for your attention



Prof. Thomas Pettke,
dipl. min. Pierre Lefèvre, and
Dr. Michael S. Krzemnicki
at the LA-ICP-MS in the
Institute of Geological
Sciences, University of Bern
(Switzerland).

before...

...and after a LA-ICP-MS session

SSEF offers LA-ICP-MS course for gemmologists in August 2009 !